

Semiautomatic Probe System

SUSS MicroTec AG introduces the BlueRay Semiautomatic Wafer Probe System. With the BlueRay's z-axis accuracy, it is now possible to be fully confident in test results from both wafers and other substrates. The BlueRay's precision guarantees a safe, repeatable electric contact with the device under test (DUT), which reduces pad damage and eliminates the need for probe mark inspection.

Suss MicroTec AG

Source URL (retrieved on 01/28/2015 - 7:17am):

<http://www.wirelessdesignmag.com/product-releases/2005/09/semiautomatic-probe-system>